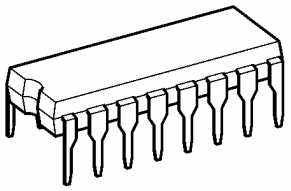
TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

TC74AC390P,TC74AC390F,TC74AC390FN

Dual Decade Counter

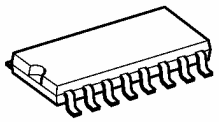
Note: xxxFN (JEDEC SOP) is not available in Japan.

TC74AC390P



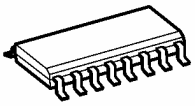
DIP16-P-300-2.54A

TC74AC390F



SOP16-P-300-1.27A

TC74AC390FN



SOL16-P-150-1.27

Weight

DIP16-P-300-2.54A	: 1.00 g (typ.)
SOP16-P-300-1.27A	: 0.18 g (typ.)
SOL16-P-150-1.27	: 0.13 g (typ.)

The TC74AC390 is an advanced high speed CMOS DUAL DECADE COUNTER fabricated with silicon gate and double-layer metal wiring C^2MOS technology.

It achieves the high speed operation similar to equivalent Bipolar Schottky TTL while maintaining the CMOS low power dissipation.

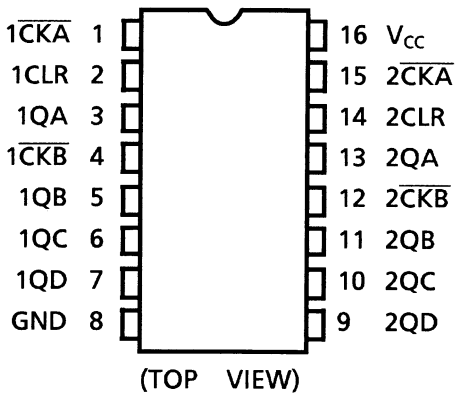
It consists of two independent 4-bit counters, each composed of a divide-by-two and a divide-by-five counter. The divide-by-two counter is incremented on the negative going transition of clock A ($\overline{CKA}$). The divided-by-five counter is incremented on the negative going transition of clock B ($\overline{CKB}$). The counter can be cascaded to form decade, bi-quinary, or various combinations up to a divide-by-100 counter. When the CLEAR input is set high, the Q outputs are set to low independent of the clock inputs.

All inputs are equipped with protection circuits against static discharge or transient excess voltage.

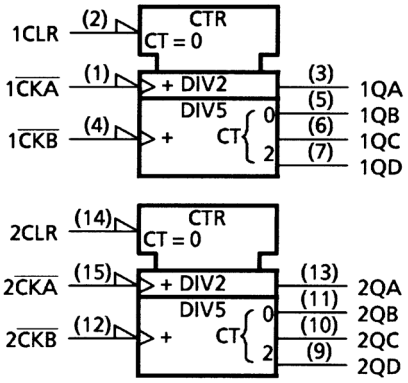
Features

- High speed: f_{max} = 160 MHz (typ.) at V_{CC} = 5 V
- Low power dissipation: I_{CC} = 8 μA (max) at Ta = 25°C
- High noise immunity: $V_{NIH} = V_{NIL}$ = 28% V_{CC} (min)
- Symmetrical output impedance: $|I_{OH}| = I_{OL}$ = 24 mA (min)
  Capability of driving 50 Ω transmission lines.
- Balanced propagation delays: $t_{pLH} \simeq t_{pHL}$
- Wide operating voltage range: V_{CC} (opr) = 2 to 5.5 V
- Pin and function compatible with 74HC390

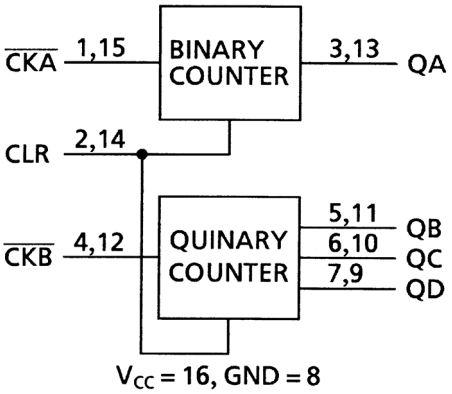
Pin Assignment



IEC Logic Symbol



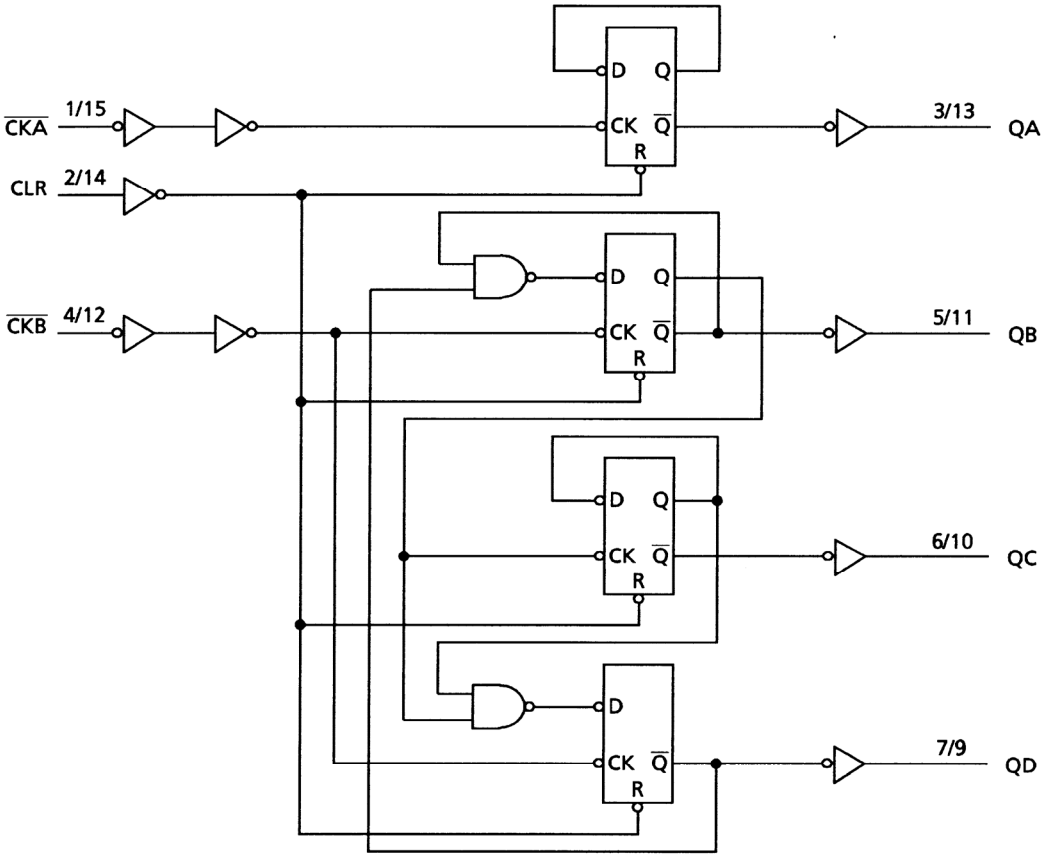
Block Daigram



Truth Table

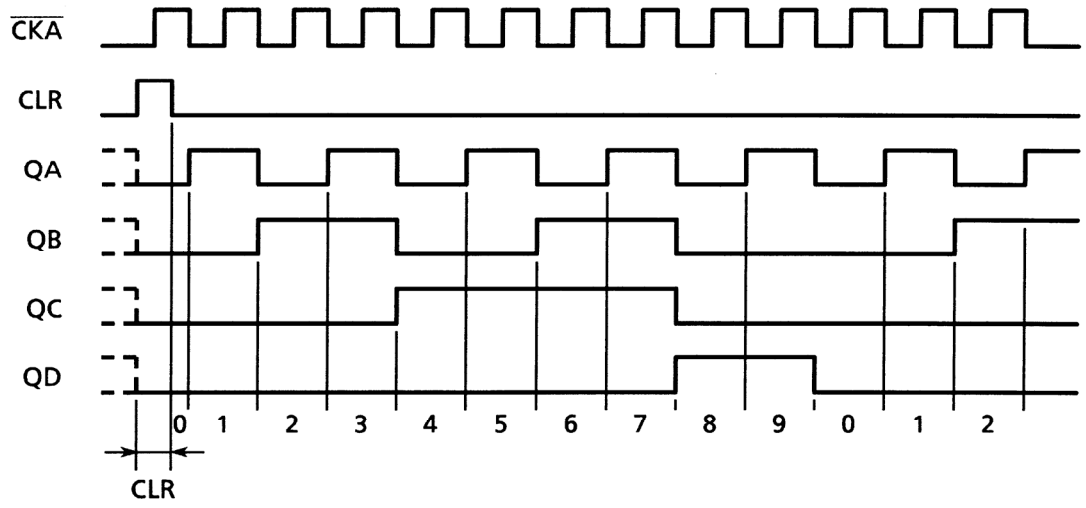
Inputs			Outputs			
$\overline{CKA}$	$\overline{CKB}$	CLR	QA	QB	QC	QD
X	X	H	L	L	L	L
↓	X	L	Binary Count Up			
X	↓	L	Quinary Count Up			

System Diagram



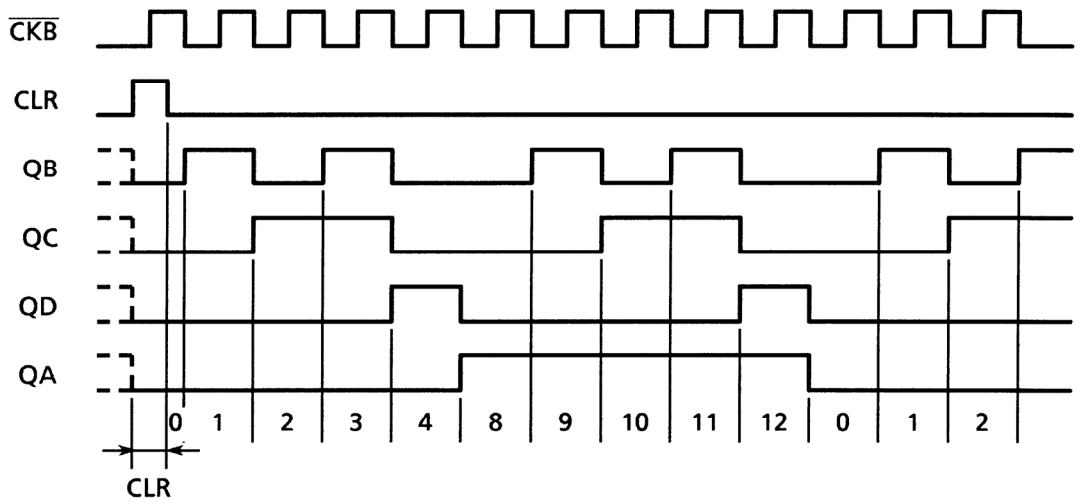
Timing Chart

(1) BCD count sequence (Note)



Note: QA connected to $\overline{CKB}$

(2) Bi-quinary count sequence (Note)



Note: QD connected to $\overline{CKA}$

Absolute Maximum Ratings (Note 1)

Characteristics	Symbol	Rating	Unit
Supply voltage range	V_{CC}	−0.5 to 7.0	V
DC input voltage	V_{IN}	−0.5 to V_{CC} + 0.5	V
DC output voltage	V_{OUT}	−0.5 to V_{CC} + 0.5	V
Input diode current	I_{IK}	±20	mA
Output diode current	I_{OK}	±50	mA
DC output current	I_{OUT}	±50	mA
DC V_{CC}/ground current	I_{CC}	±200	mA
Power dissipation	P_D	500 (DIP) (Note 2)/180 (SOP)	mW
Storage temperature	T_{stg}	−65 to 150	°C

Note 1: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.
Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.
Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook (“Handling Precautions”/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 2: 500 mW in the range of Ta = −40 to 65°C. From Ta = 65 to 85°C a derating factor of −10 mW/°C should be applied up to 300 mW.

Operating Ranges (Note)

Characteristics	Symbol	Rating	Unit
Supply voltage	V_{CC}	2.0 to 5.5	V
Input voltage	V_{IN}	0 to V_{CC}	V
Output voltage	V_{OUT}	0 to V_{CC}	V
Operating temperature	T_{opr}	−40 to 85	°C
Input rise and fall time	dt/dV	0 to 100 (V_{CC} = 3.3 ± 0.3 V) 0 to 20 (V_{CC} = 5 ± 0.5 V)	ns/V

Note: The operating ranges must be maintained to ensure the normal operation of the device.
Unused inputs must be tied to either VCC or GND.

Electrical Characteristics

DC Characteristics

Characteristics	Symbol	Test Condition		V_{CC} (V)	Ta = 25°C Min	Ta = 25°C Typ.	Ta = 25°C Max	Ta = −40 to 85°C Min	Ta = −40 to 85°C Max	Unit
High-level input voltage	V_{IH}	—		2.0	1.50	—	—	1.50	—	V
				3.0	2.10	—	—	2.10	—	
				5.5	3.85	—	—	3.85	—	
Low-level input voltage	V_{IL}	—		2.0	—	—	0.50	—	0.50	V
				3.0	—	—	0.90	—	0.90	
				5.5	—	—	1.65	—	1.65	
High-level output voltage	V_{OH}	V_{IN} = V_{IH} or V_{IL}	I_{OH} = −50 μA	2.0	1.9	2.0	—	1.9	—	V
				3.0	2.9	3.0	—	2.9	—	
				4.5	4.4	4.5	—	4.4	—	
			I_{OH} = −4 mA	3.0	2.58	—	—	2.48	—	
			I_{OH} = −24 mA	4.5	3.94	—	—	3.80	—	
			I_{OH} = −75 mA (Note)	5.5	—	—	—	3.85	—	
Low-level output voltage	V_{OL}	V_{IN} = V_{IH} or V_{IL}	I_{OL} = 50 μA	2.0	—	0.0	0.1	—	0.1	V
				3.0	—	0.0	0.1	—	0.1	
				4.5	—	0.0	0.1	—	0.1	
			I_{OL} = 12 mA	3.0	—	—	0.36	—	0.44	
			I_{OL} = 24 mA	4.5	—	—	0.36	—	0.44	
			I_{OL} = 75 mA (Note)	5.5	—	—	—	—	1.65	
Input leakage current	I_{IN}	V_{IN} = V_{CC} or GND		5.5	—	—	±0.1	—	±1.0	μA
Quiescent supply current	I_{CC}	V_{IN} = V_{CC} or GND		5.5	—	—	8.0	—	80.0	μA

Note: This spec indicates the capability of driving 50 Ω transmission lines.

One output should be tested at a time for a 10 ms maximum duration.

Timing Requirements (input: $t_r = t_f = 3$ ns)

Characteristics	Symbol	Test Condition		Ta = 25°C Limit	Ta = −40 to 85°C Limit	Unit
Minimum pulse width ($\overline{CKA}$, $\overline{CKB}$)	$t_{W(H)}$	—	V_{CC} (V)			
			3.3 ± 0.3	7.0	7.0	ns
	$t_{W(L)}$		5.0 ± 0.5	5.0	5.0	
Minimum pulse width (CLR)	$t_{W(H)}$	—	3.3 ± 0.3	7.0	7.0	ns
			5.0 ± 0.5	5.0	5.0	
Minimum removal time	t_{rem}	—	3.3 ± 0.3	7.0	7.0	ns
			5.0 ± 0.5	3.5	3.5	

AC Characteristics (C_L = 50 pF, R_L = 500 Ω, input: $t_r = t_f$ = 3 ns)

Characteristics	Symbol	Test Condition		Ta = 25°C			Ta = −40 to 85°C		Unit
			V_{CC} (V)	Min	Typ.	Max	Min	Max	
Propagation delay time ($\overline{CKA}$ -QA)	t_{pLH} t_{pHL}	—	3.3 ± 0.3 5.0 ± 0.5	— —	8.2 5.5	14.0 8.4	1.0 1.0	16.0 9.6	ns
Propagation delay time ($\overline{CKA}$ -QC)	t_{pLH} t_{pHL}	QA connected to $\overline{CKB}$	3.3 ± 0.3 5.0 ± 0.5	— —	17.0 10.5	30.0 17.5	1.0 1.0	34.0 20.0	ns
Propagation delay time ($\overline{CKB}$ -QB, QD)	t_{pLH} t_{pHL}	—	3.3 ± 0.3 5.0 ± 0.5	— —	8.8 6.0	14.9 9.4	1.0 1.0	17.0 10.7	ns
Propagation delay time ($\overline{CKB}$ -QC)	t_{pLH} t_{pHL}	—	3.3 ± 0.3 5.0 ± 0.5	— —	11.0 7.1	18.8 11.3	1.0 1.0	21.5 12.8	ns
Propagation delay time (CLR-Qn)	t_{pHL}	—	3.3 ± 0.3 5.0 ± 0.5	— —	7.7 5.7	12.5 8.5	1.0 1.0	14.3 9.7	ns
Maximum clock frequency ($\overline{CKA}$)	f_{max}	—	3.3 ± 0.3 5.0 ± 0.5	60 100	120 180	— —	60 100	— —	MHz
Maximum clock frequency ($\overline{CKB}$)	f_{max}	—	3.3 ± 0.3 5.0 ± 0.5	45 90	90 140	— —	45 90	— —	MHz
Input capacitance	C_{IN}	—		—	5	10	—	10	pF
Power dissipation capacitance	C_{PD} (Note)	—		—	40	—	—	—	pF

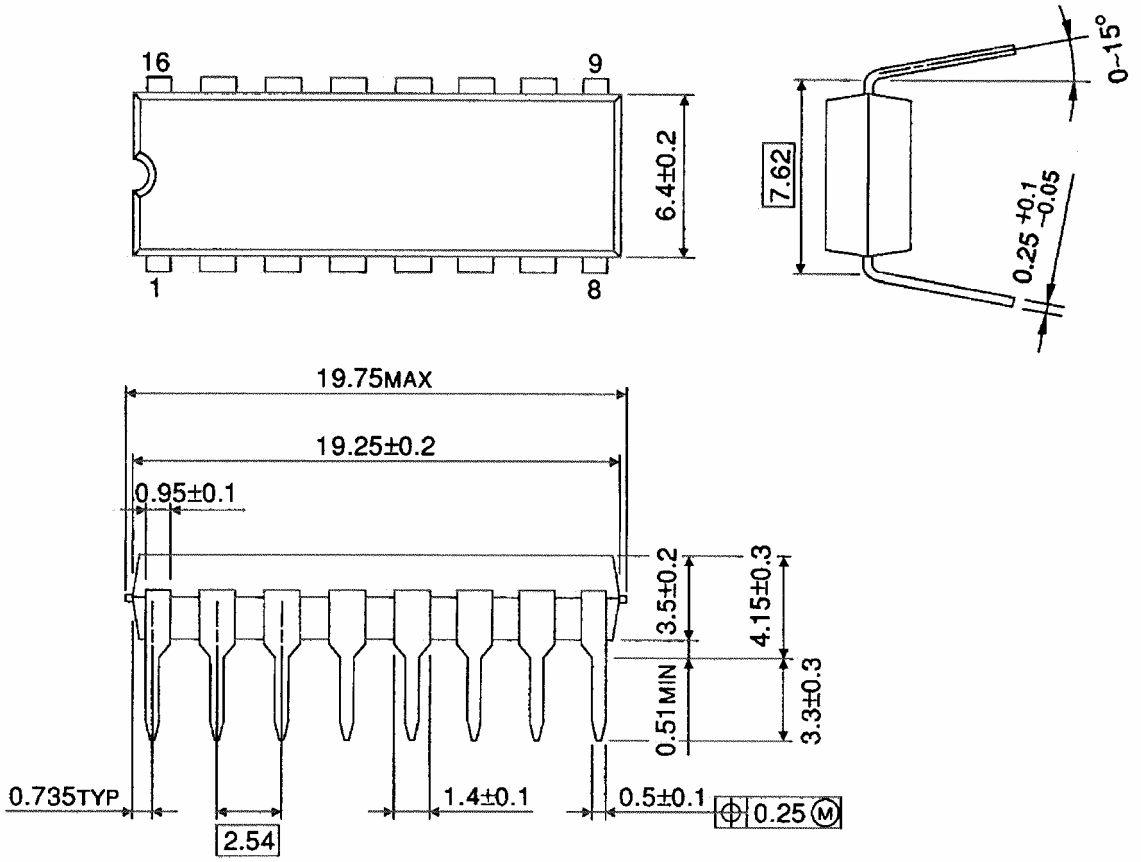
Note: C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation:

$$I_{CC}\ (opr) = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/2 \text{ (per counter)}$$

Package Dimensions

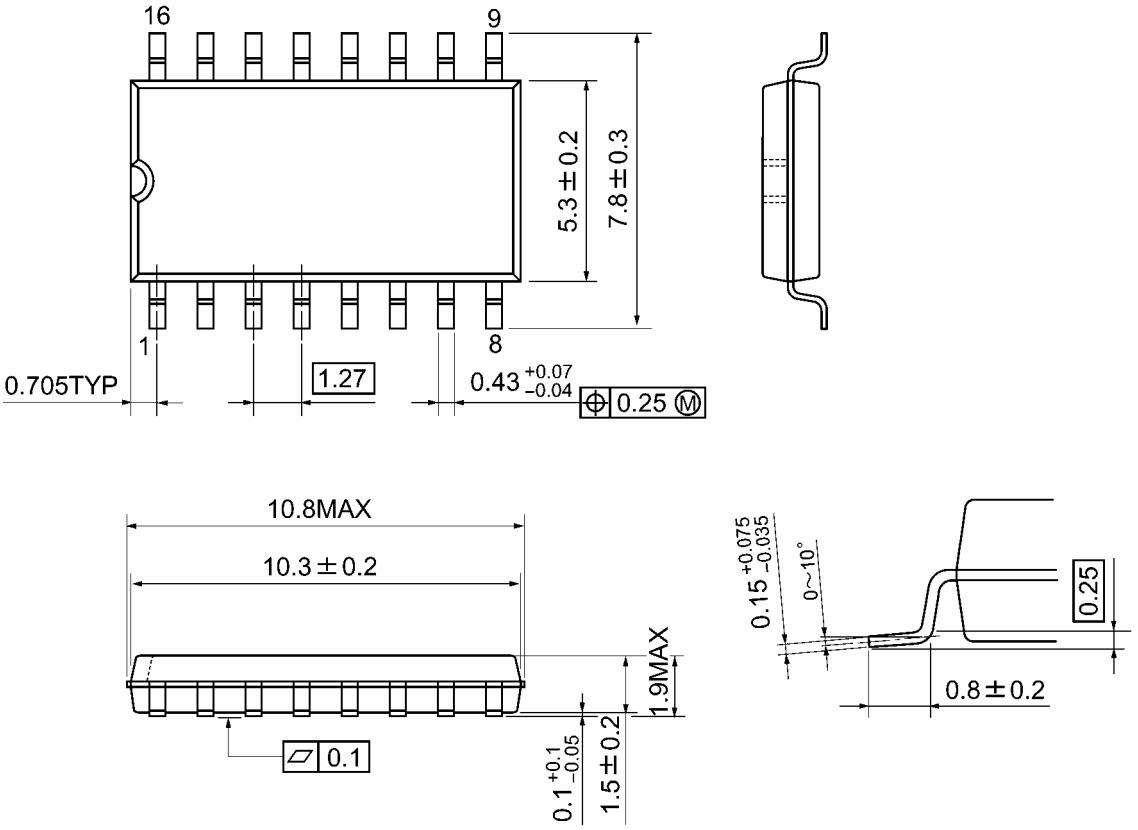
DIP16-P-300-2.54A Unit : mm



Weight: 1.00 g (typ.)

Package Dimensions

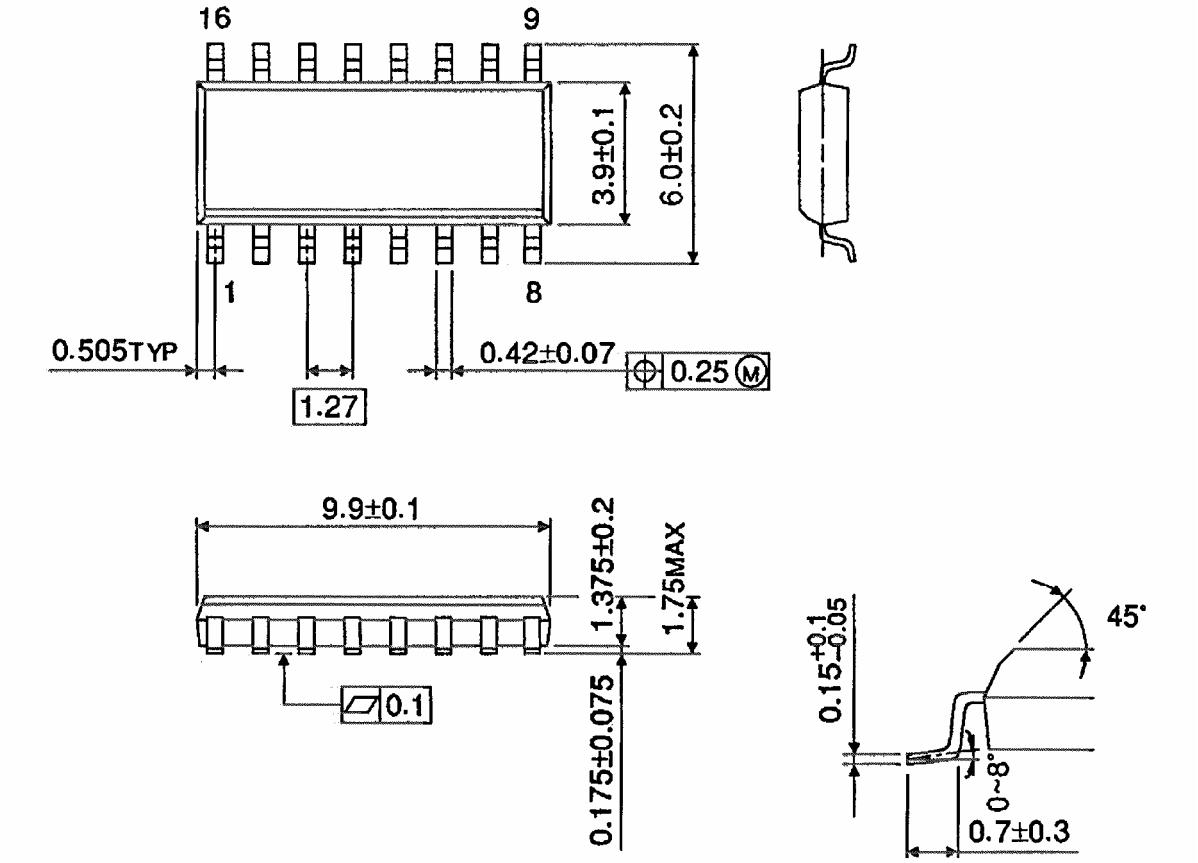
SOP16-P-300-1.27A Unit: mm



Weight: 0.18 g (typ.)

Package Dimensions (Note)

SOL16-P-150-1.27 Unit : mm



Note: This package is not available in Japan.

Weight: 0.13 g (typ.)

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20070701-EN GENERAL

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